Notice of References Cited

Application/Control No.

Applicant(s)/Patent Under Reexamination HARUKI ET AL.

Examiner

Ryan J Hesseltine

Applicant(s)/Patent Under Reexamination HARUKI ET AL.

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,559,504	09-1996	Itsumi et al.	340/5.53
*	В	US-5,867,218	02-1999	Matsuzaki et al.	348/373
*	C	US-5,978,495	11-1999	Thomopoulos et al.	382/124
*	D	US-6,118,485	09-2000	Hinoue et al.	348/373
*	Е	US-6,173,405	01-2001	Nagel, Paul	713/200
*	F	US-6,213,403	04-2001	Bates, III, Charles Linsday	235/492
*	G	US-6,234,389	05-2001	Valliani et al.	235/380
*	Ξ	US-6,330,151	12-2001	Bates, III, Charles Linsday	361/686
*	_	US-6,357,663	03-2002	Takahashi et al.	235/486
*	7	US-6,525,932	02-2003	Ohnishi et al.	361/686
*	К	US-6,592,031	07-2003	Klatt, Dieter	235/382
*	L	US-6,628,814	09-2003	Shapiro, Yury	382/127
*	М	US-6,631,201	10-2003	Dickinson et al.	382/124

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2000293688 A	10-2000	Japan	NIIZAKI et al.	G06T 07/00
*	0	JP 2001069391 A	03-2001	Japan	KANBE et al.	H04N 05/225
	Р					
	Q					
	R					
1	s					
	Т					

NON-PATENT DOCUMENTS

	NORTH ATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.